# **AUTOMOTIVE GRADE**



# AUIRF3004WL

WIDEL FAD HEXFET® Power MOSFET

### **Features**

- Advanced Process Technology
- Ultra Low On-Resistance
- 50% Lower Lead Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*

# G S

V <sub>(BR)DSS</sub>	40V	
R <sub>DS(on)</sub> typ.	<b>1.27m</b> Ω	
max.	1.40m $\Omega$	
I <sub>D (Silicon Limited)</sub>	386A ①	
D (Package Limited)	240A	

# Description

Specifically design for automotive applications this Widelead TO-262 package part has the advantage of having over 50% lower lead resistance and delivering over 20% lower Rds(on) when compared with a traditional TO-262 package housing the same silicon die. This greatly helps in reducing condition losses, achieving higher current levels or enabling a system to run cooler and have improved efficiency. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating . These features combine to make this design an extremely efficient and reliable device for use in Automotive and other applications.



G	D	S
Gate	Drain	Source

# **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (T<sub>A</sub>) is 25°C, unless otherwise specified.

	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	<b>386</b> ①	
$I_D @ T_C = 100^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	<b>273</b> ①	
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	240	<b>]</b> ^
I <sub>DM</sub>	Pulsed Drain Current ②	1544	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	375	W
	Linear Derating Factor	2.5	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS (Thermally limited)</sub>	Single Pulse Avalanche Energy ③	470	mJ
I <sub>AR</sub>	Avalanche Current ②	See Fig. 14, 15, 22a, 22b,	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ②		mJ
dv/dt	Peak Diode Recovery ④	6.1	V/ns
$T_J$	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	

### Thermal Resistance

	Parameter	Тур.	Max.	Units				
$R_{\theta JC}$	Junction-to-Case ®		0.40	°C/W				

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<sup>\*</sup>Qualification standards can be found at http://www.irf.com/

# Static Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40		_	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.038		V/°C	Reference to 25°C, $I_D = 5mA$ $\textcircled{5}$
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		1.27	1.40	mΩ	$V_{GS} = 10V, I_D = 195A $ $\bigcirc$
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
gfs	Forward Transconductance	330			S	$V_{DS} = 10V, I_{D} = 195A$
$R_G$	Internal Gate Resistance		2.7		Ω	
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20		$V_{DS} = 40V$ , $V_{GS} = 0V$
				250	μA	$V_{DS} = 32V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			100	nΛ	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage			-100	nA	V <sub>GS</sub> = -20V

## Dynamic Electrical Characteristics @ T<sub>1</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$\overline{Q_g}$	Total Gate Charge		140	210		$I_D = 232A$
$Q_{gs}$	Gate-to-Source Charge		53		nC	$V_{DS} = 20V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		49		nC	V <sub>GS</sub> = 10V ⑤
Q <sub>sync</sub>	Total Gate Charge Sync. (Q <sub>g</sub> - Q <sub>gd</sub> )		91			$I_D = 232A, V_{DS} = 0V, V_{GS} = 10V $ §
t <sub>d(on)</sub>	Turn-On Delay Time		19			$V_{DD} = 26V$
t <sub>r</sub>	Rise Time		220			$I_D = 232A$
t <sub>d(off)</sub>	Turn-Off Delay Time		90		ns	$R_G = 2.7\Omega$
t <sub>f</sub>	Fall Time		130			V <sub>GS</sub> = 10V ⑤
C <sub>iss</sub>	Input Capacitance		9450			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		1930			$V_{DS} = 32V$
C <sub>rss</sub>	Reverse Transfer Capacitance		975		рF	f = 1.0MHz, See Fig.5
C <sub>oss</sub> eff. (ER)	Effective Output Capacitance (Energy Related)		2330			$V_{GS} = 0V$ , $V_{DS} = 0V$ to 32V $\odot$ , See Fig.11
C <sub>oss</sub> eff. (TR)	Effective Output Capacitance (Time Related)		2815		Ĩ	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 32V  $

### **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current			386①		MOSFET symbol
	(Body Diode)				A	showing the
I <sub>SM</sub>	Pulsed Source Current			1544	^	integral reverse
	(Body Diode) ②					p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25$ °C, $I_S = 195$ A, $V_{GS} = 0$ V $\$$
t <sub>rr</sub>	Reverse Recovery Time		41	62		$T_J = 25^{\circ}C$ $V_R = 34V$ ,
			51	77	ns	$T_{\rm J} = 125^{\circ} C$ $I_{\rm F} = 232 A$
Q <sub>rr</sub>	Reverse Recovery Charge		62	93		$T_J = 25^{\circ}C$ di/dt = 100A/ $\mu$ s $^{\circ}$
			99	149	nC	$T_{\rm J} = 125^{\circ}{\rm C}$
I <sub>RRM</sub>	Reverse Recovery Current		2.3		Α	$T_J = 25^{\circ}C$
t <sub>on</sub>	Forward Turn-On Time	Intrins	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

### Notes:

- temperature. Package limitation current is 240A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.(Refer to AN-1140
  - http://www.irf.com/technical-info/appnotes/an-1140.pdf
- 2 Repetitive rating; pulse width limited by max. junction temperature.
- $R_G = 50\Omega$ ,  $I_{AS} = 232A$ ,  $V_{GS} = 10V$ . Part not recommended for use above this value.
- ⑤ Pulse width  $\leq$  400 $\mu$ s; duty cycle  $\leq$  2%.
- $\mbox{\ensuremath{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath}\ens$ as  $C_{\text{oss}}$  while  $V_{\text{DS}}$  is rising from 0 to 80%  $V_{\text{DSS}}$ .
- $\ensuremath{\mathfrak{O}}$  Coss eff. (ER) is a fixed capacitance that gives the same energy as Coss while VDS is rising from 0 to 80% VDSS.
- $\$  R<sub> $\theta$ </sub> is measured at T<sub>J</sub> approximately 90°C.

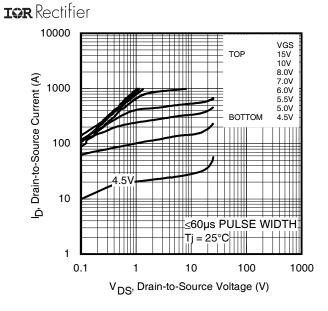


Fig 1. Typical Output Characteristics

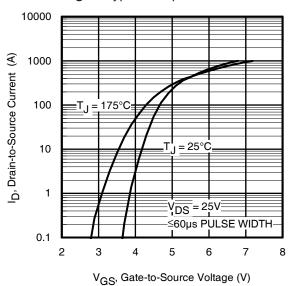


Fig 3. Typical Transfer Characteristics

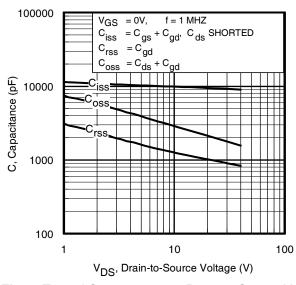


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

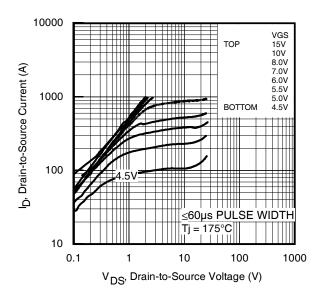


Fig 2. Typical Output Characteristics

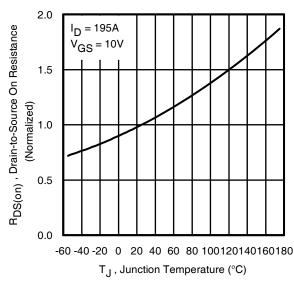


Fig 4. Normalized On-Resistance vs. Temperature

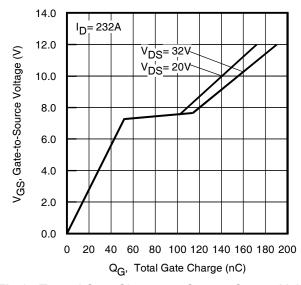


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

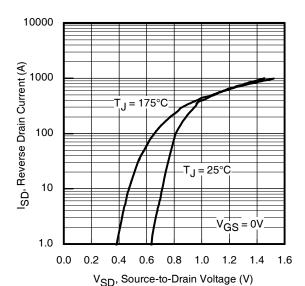


Fig 7. Typical Source-Drain Diode Forward Voltage

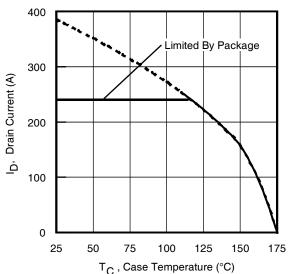


Fig 9. Maximum Drain Current vs. Case Temperature

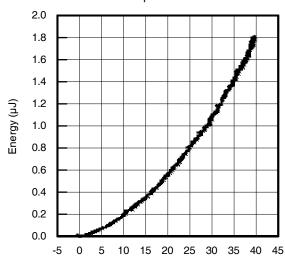


Fig 11. Typical C<sub>OSS</sub> Stored Energy

V<sub>DS</sub>. Drain-to-Source Voltage (V)

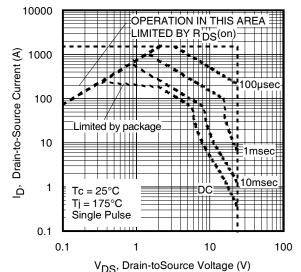


Fig 8. Maximum Safe Operating Area

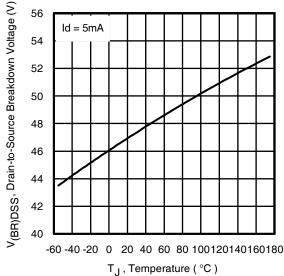


Fig 10. Drain-to-Source Breakdown Voltage

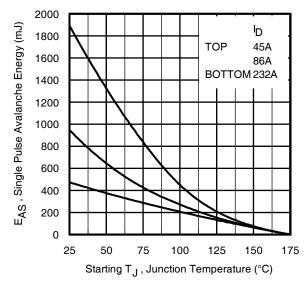


Fig 12. Maximum Avalanche Energy vs. DrainCurrent

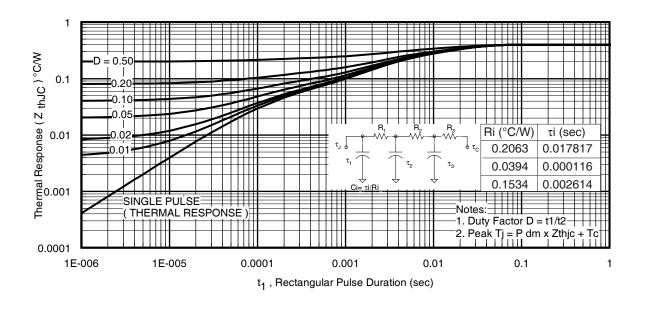


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

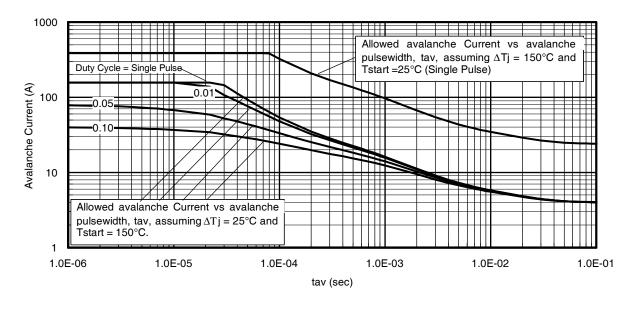
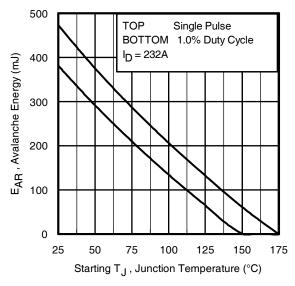


Fig 14. Typical Avalanche Current vs. Pulsewidth



Notes on Repetitive Avalanche Curves, Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- Avalanche failures assumption:
   Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>imax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT<sub>imax</sub> is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figure 22a, 22b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 14, 15).

 $t_{av}$  = Average time in avalanche.

 $D = Duty cycle in avalanche = t_{av} \cdot f$ 

 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D\;(ave)} &= 1/2\;(\;1.3 \cdot BV \cdot I_{av}) = \Delta T/\;Z_{thJC} \\ I_{av} &= 2\Delta T/\;[1.3 \cdot BV \cdot Z_{th}] \\ E_{AS\;(AR)} &= P_{D\;(ave)} \cdot t_{av} \end{split}$$

Fig 15. Maximum Avalanche Energy vs. Temperature

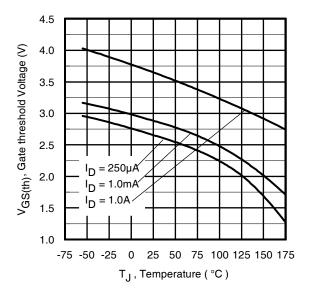


Fig 16. Threshold Voltage vs. Temperature

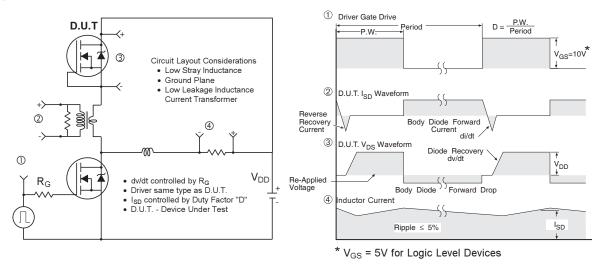


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

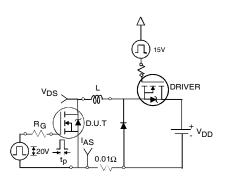


Fig 22a. Unclamped Inductive Test Circuit

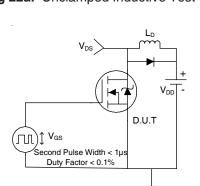


Fig 23a. Switching Time Test Circuit

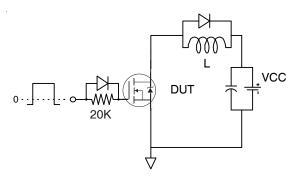


Fig 24a. Gate Charge Test Circuit www.irf.com

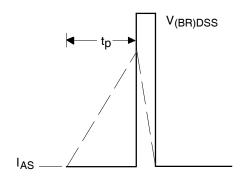


Fig 22b. Unclamped Inductive Waveforms

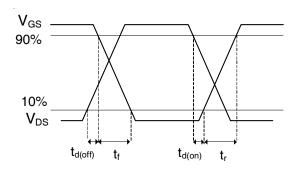


Fig 23b. Switching Time Waveforms

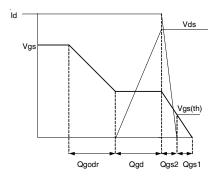
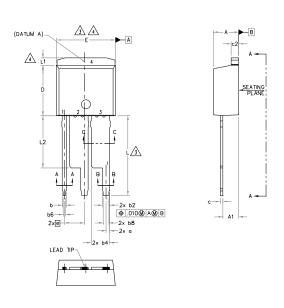


Fig 24b. Gate Charge Waveform

# TO-262 WideLead Package Outline

Dimensions are shown in millimeters (inches)



					_	
S Y M	DIMENSIONS					
В	MILLIM	ETERS	INC	HES	O T E S	
0 L	MIN.	MAX.	MIN.	MAX.	E S	
Α	4.06	4.83	.160	.190		
A1	2.03	3.02	.080	.119		
a	0.20	0.51	.008	.020		
ь	0.51	0.91	.020	.036	5	
ь1	0.51	0.81	.020	.032		
b2	1.07	1,47	0.42	.058		
b3	1.07	1,37	.042	.054	5	
b4	3.05	3.45	.120	.136		
ь5	3.05	3.35	.120	.132	5	
b6	0.25	0.61	.010	.024		
ь7	0.25	0.51	.010	.020	5	
ь8	0.76	1,17	.030	.046		
b9	0.76	1.07	.030	.022	5	
С	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1,14	1,65	.045	.065		
D	8.51	9.65	.335	.380	3	
D1	6.86	7.42	.270	.292	4	
E	9.65	10.67	.380	.420	3,4	
E1	6,22	8.48	.245	.334	4	
e	3.81	3,81 BSC		.150 BSC		
L	13.46	14,10	.530	.555		
L1	-	1.65	-	.065	4	
L2	8,64	9.40	,340	.370		

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

ADMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5 DIMENSION 63, 65, 67, 69 AND c1 APPLY TO BASE METAL ONLY.

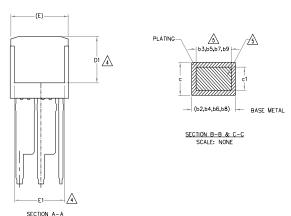
6. CONTROLLING DIMENSION: INCH.

7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(mox.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

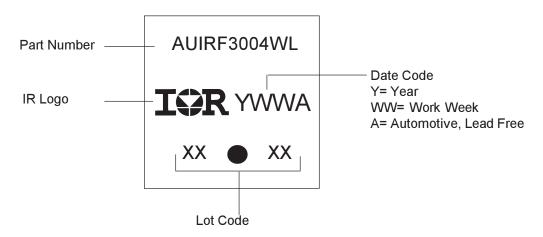
### LEAD ASSIGNMENTS

### HEXFET

1.- GATE 2.- DRAIN 3.- SOURCE



# TO-262 WideLead Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

International
TOR Rectifier

**Ordering Information** 

Base part number	Package Type	Standard Pack	Complete Part Number	
		Form	Quantity	
AUIRF3004WL	TO-262 WideLead	Tube	50	AUIRF3004WL

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101 N. Sepulveda Blvd., El Segundo, California 90245
Tel: (310) 252-7105